



ALPHA & OMEGA
SEMICONDUCTOR

AO6409A

20V P-Channel MOSFET

General Description

The AO6409A uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch applications.

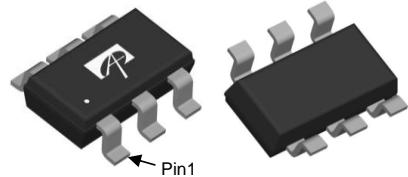
Product Summary

V_{DS}	-20V
I_D (at $V_{GS}=-4.5V$)	-5.5A
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 41mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$)	< 53mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$)	< 65mΩ

ESD protected



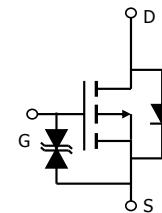
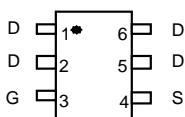
Top View



TSOP6

Bottom View

Top View



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current	I_D	-5.5	A
Current $T_A=70^\circ\text{C}$		-4.2	
Pulsed Drain Current ^C	I_{DM}	-30	
Power Dissipation ^B	P_D	2.1	W
$T_A=25^\circ\text{C}$		1.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	48	60	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		75	90	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	37	45	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			± 10	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.3	-0.57	-0.9	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-5.5\text{A}$ $T_J=125^\circ\text{C}$	34	41		$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-4\text{A}$	49	59		$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-2\text{A}$	42	53		$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-5.5\text{A}$	52	65		$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$	-0.64	-1		V
I_s	Maximum Body-Diode Continuous Current				-2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$	600	751	905	pF
C_{oss}	Output Capacitance		80	115	150	pF
C_{rss}	Reverse Transfer Capacitance		48	80	115	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	6	13	20	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-5.5\text{A}$	7.4	9.3	11	nC
Q_{gs}	Gate Source Charge		0.8	1	1.2	nC
Q_{gd}	Gate Drain Charge		1.3	2.2	3.1	nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=1.8\Omega, R_{\text{GEN}}=3\Omega$		13		ns
t_r	Turn-On Rise Time			9		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			19		ns
t_f	Turn-Off Fall Time			29		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-5.5\text{A}, dI/dt=500\text{A}/\mu\text{s}$	20	26	32	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-5.5\text{A}, dI/dt=500\text{A}/\mu\text{s}$	40	51	62	nC

A. The value of $R_{\text{IJ(A)}}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

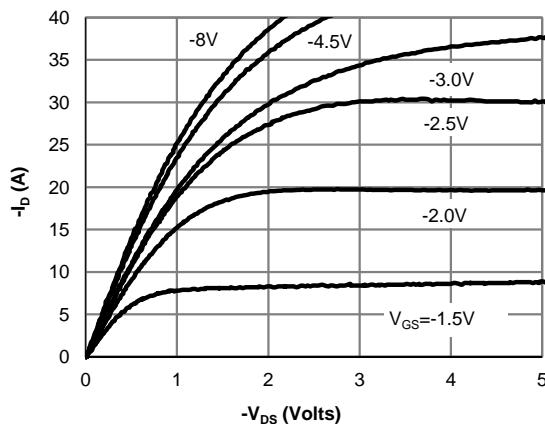
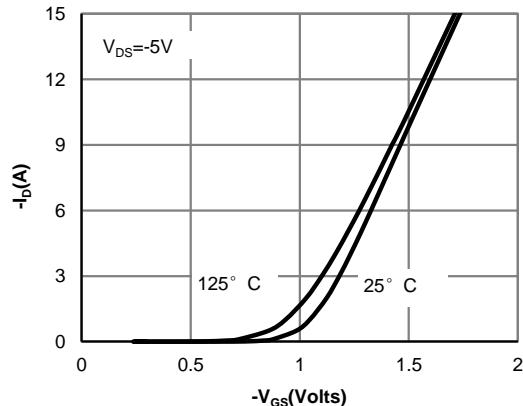
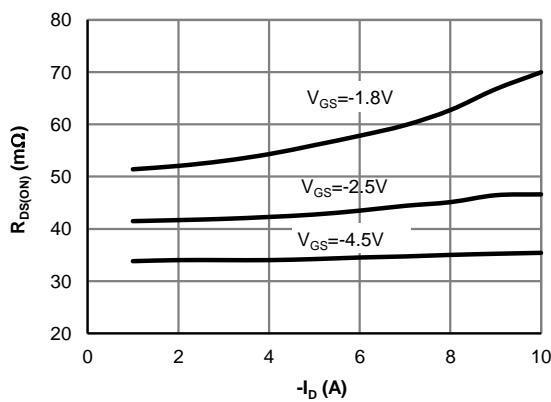
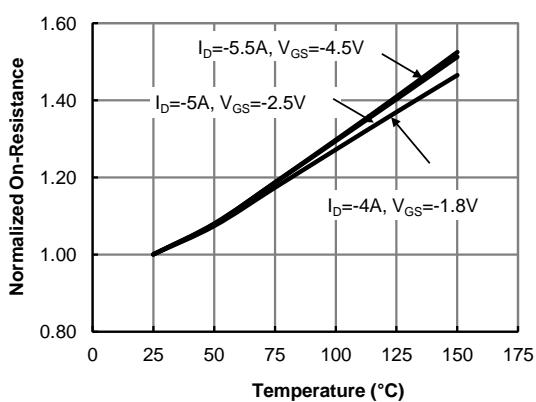
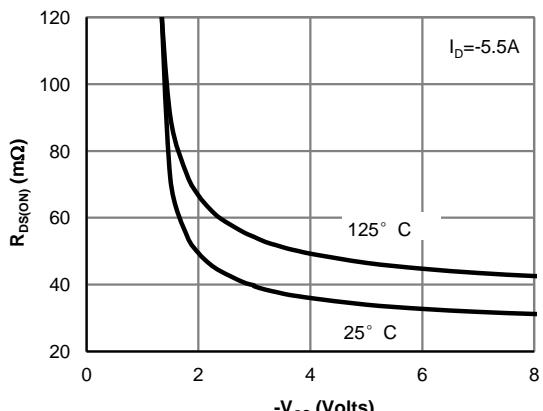
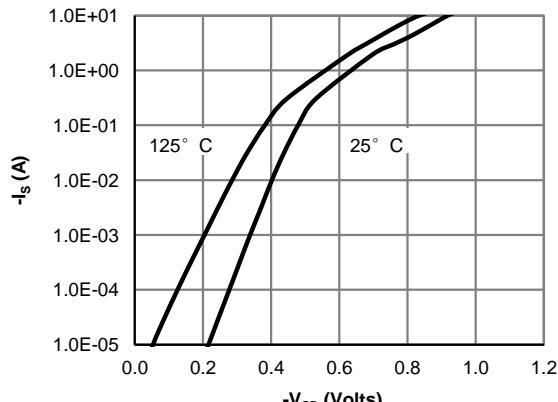
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

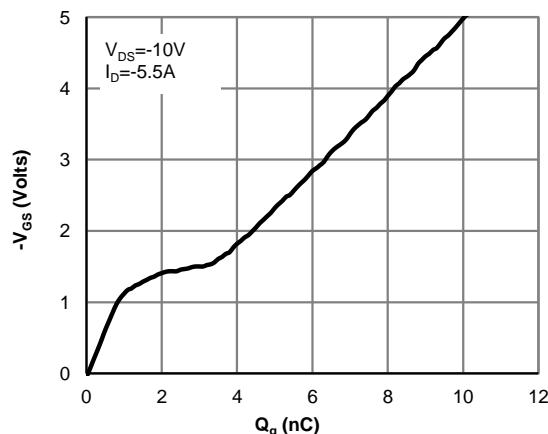
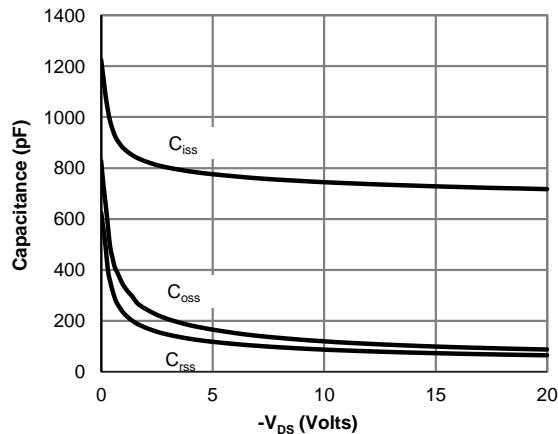
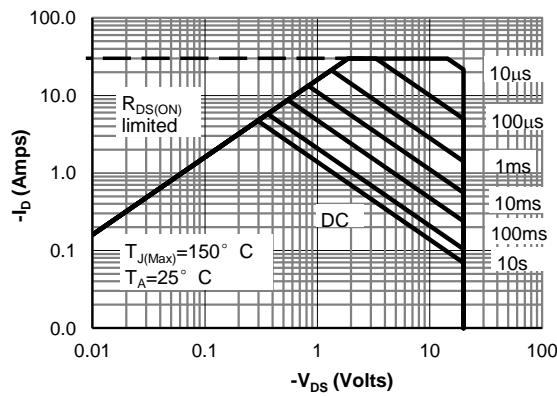
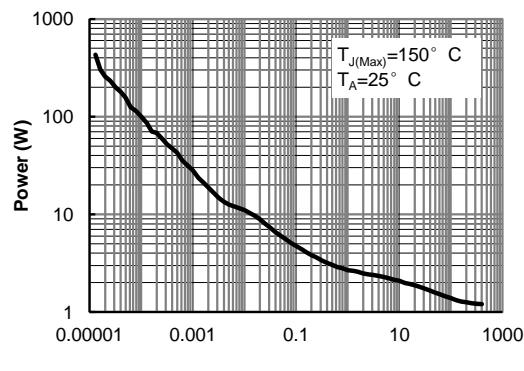
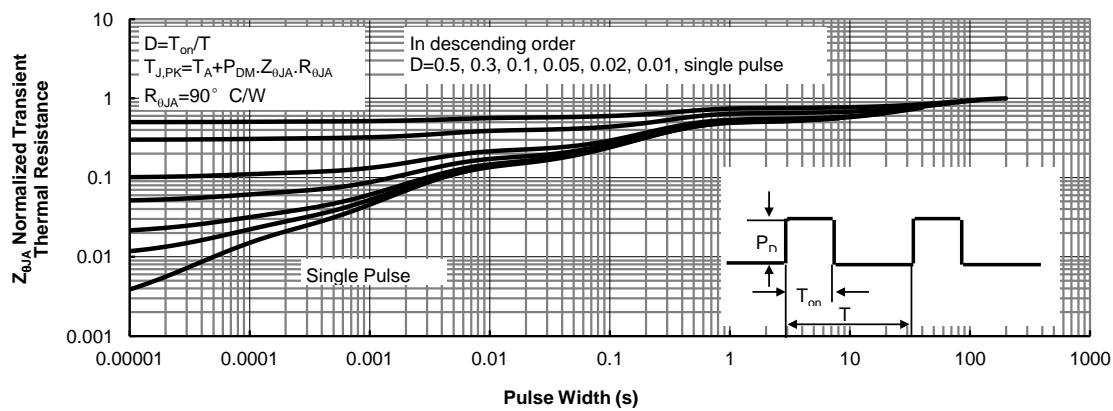
D. The $R_{\text{IJ(A)}}$ is the sum of the thermal impedance from junction to lead R_{IJL} and lead to ambient.

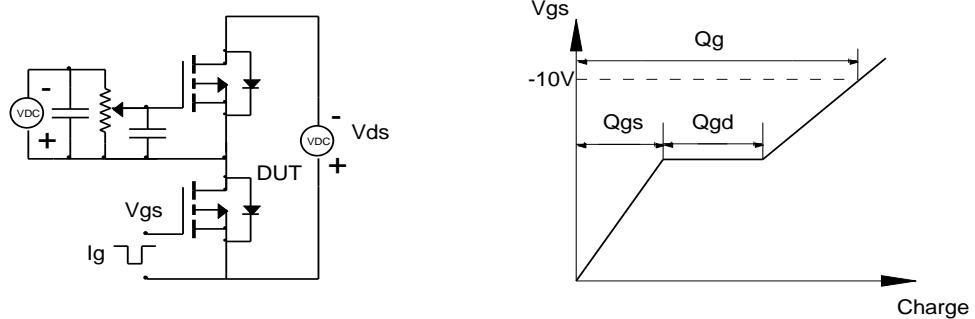
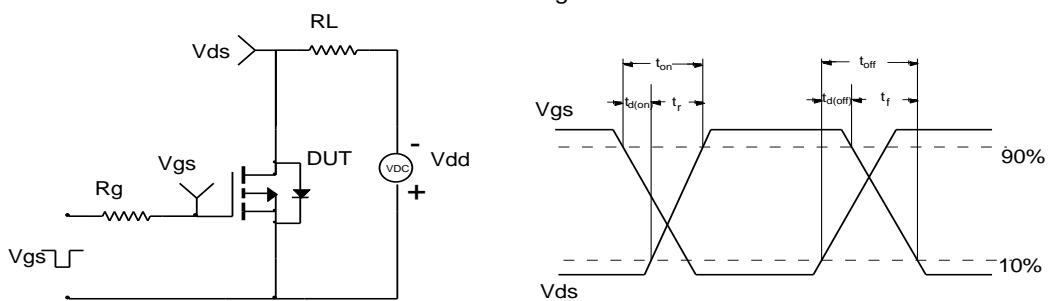
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
